Application/Control No. Applicant(s)/Patent Under Reexamination 10/647,502 NINOMIYA ET AL. Notic of R ferenc s Cited Examiner Art Unit Page 1 of 1 MUHAMMAD N. EDUN 2627 **U.S. PATENT DOCUMENTS Document Number** Date Classification Name MM-YYYY Country Code-Number-Kind Code * US-2002/0034151 03-2002 Nakajima, Toshihiro 369/190 Α * 09-2002 Raaymakers, Jeroen Arnoldus Leonardus Johannes US-2002/0131347 369/44.32 В US-C US-D US-Ε US-US-G US-US-US-US-US-US-M **FOREIGN PATENT DOCUMENTS Document Number** Date Country Classification Name Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q S **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)

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